

A New Smart Stacking Technology
for 3D-LSIs

Mitsumasa Koyanagi
(Tohoku Univ./Japan)



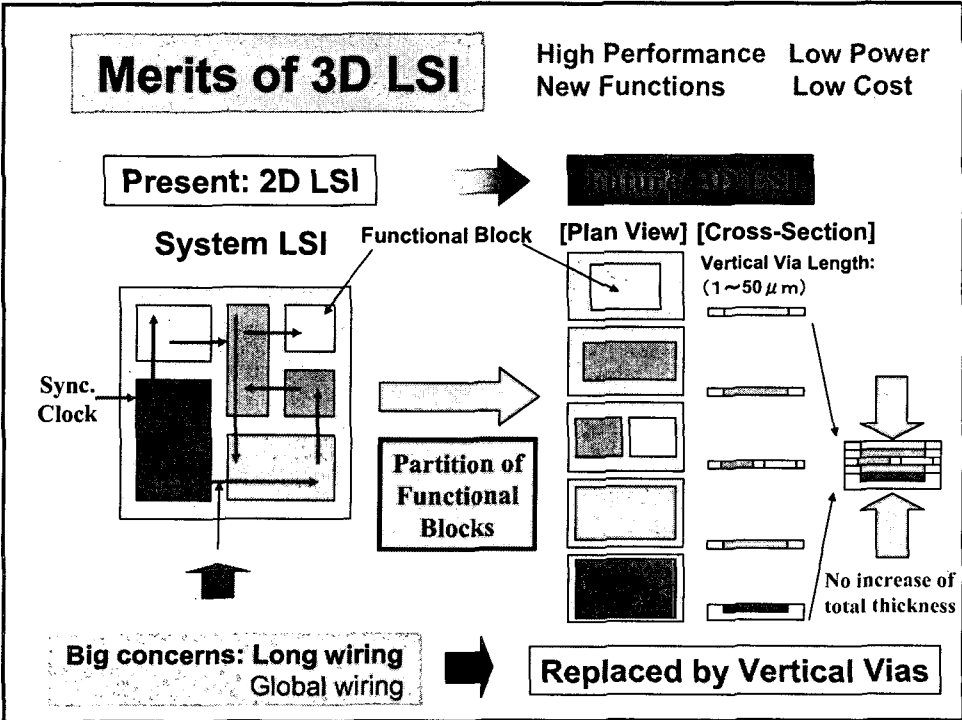
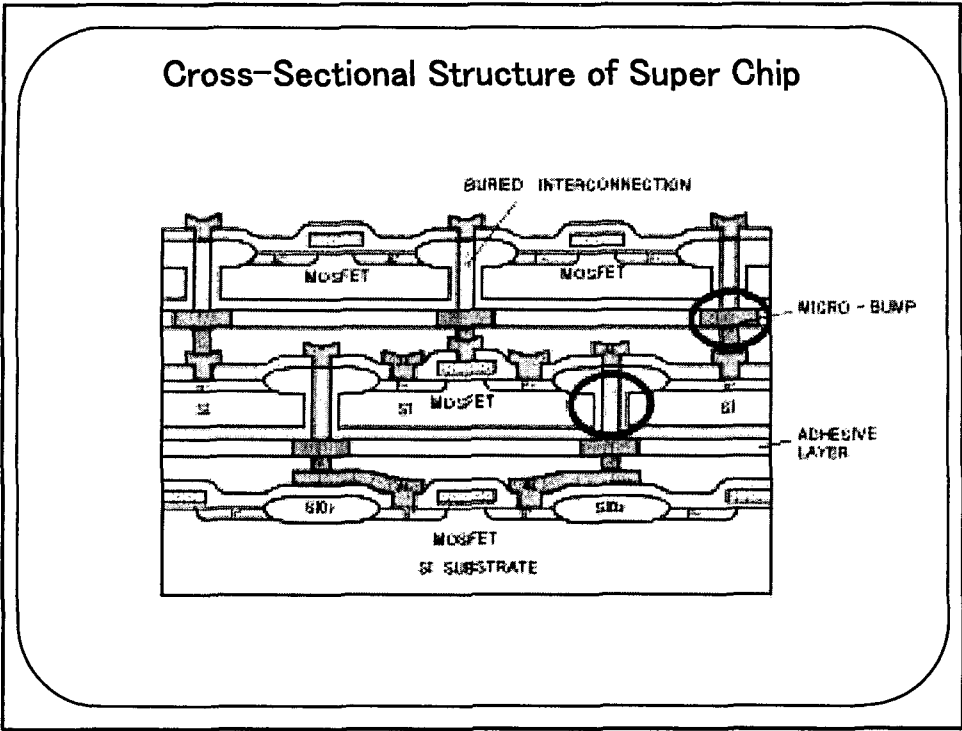
A New Smart Stacking Technology for 3D-LSIs

Mitsu Koyanagi

**Dept. of Bioengineering and Robotics,
Tohoku University, Japan**

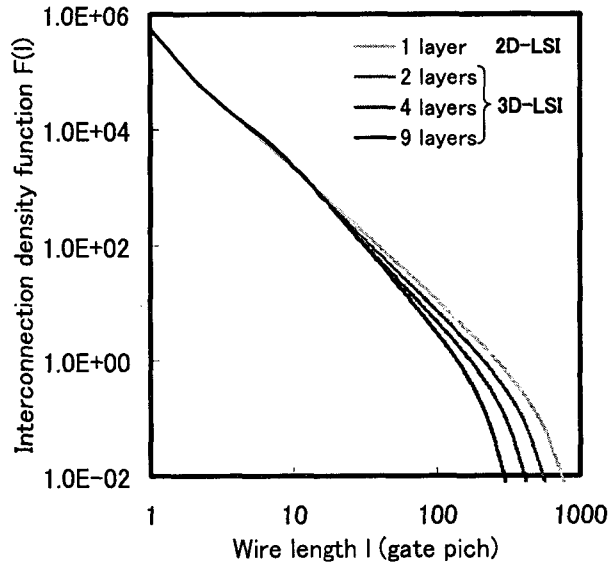
Outline

- 1. Introduction**
- 2. Advantages of 3D LSI**
- 3. Smart-Stack 3D Integration Technology**
- 4. Fabrication and Evaluation 3D LSI Test Chips**
- 5. Applications of Fabricated 3D LSI Chips**
- 6. Summary**

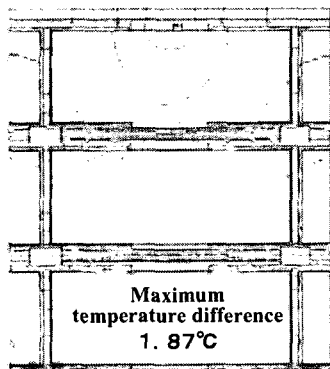


Interconnection Length Distribution in LSIs

(Vertical interconnection relative length $d=5$)

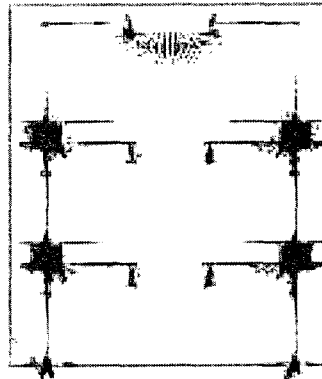


Simulated Heat Flow in 3D Structure



(a) Contour map of isothermal lines

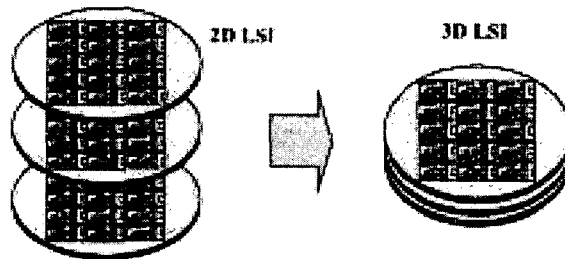
Power of heat provided to heat source: 58.5 mW
Temperature at the bottom: 0°C



(b) Heat flow distribution

Distance between heat source and buried interconnection: 31.9 μm
Micro-bump size: 10 $\mu\text{m} \times 10 \mu\text{m}$
Diameter of buried interconnection: 2.5 μm
Si thickness: 30 μm

A new 3D integration technology using a novel wafer level stacking method



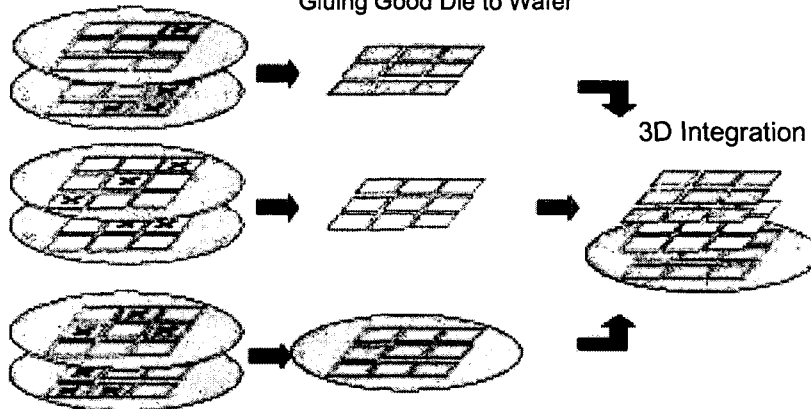
Advantages of our 3D Integrating Technology

- Different LSI wafers, which were independently fabricated are vertically stacked to form 3D LSI.
Decreasing of total process time
- Compatible with normal LSI process.
No needing an excessive increase of processing step and complexity
- High density short interconnection can be formed.
- Increasing system performance (Parallel Processing)

Fabrication Method for Super Chip Using Smart-Stack Technology

Known Good Die (KGD)

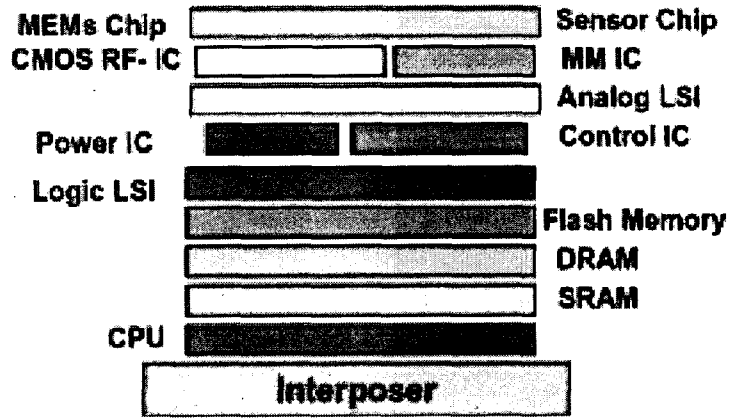
Gluing Good Die to Wafer



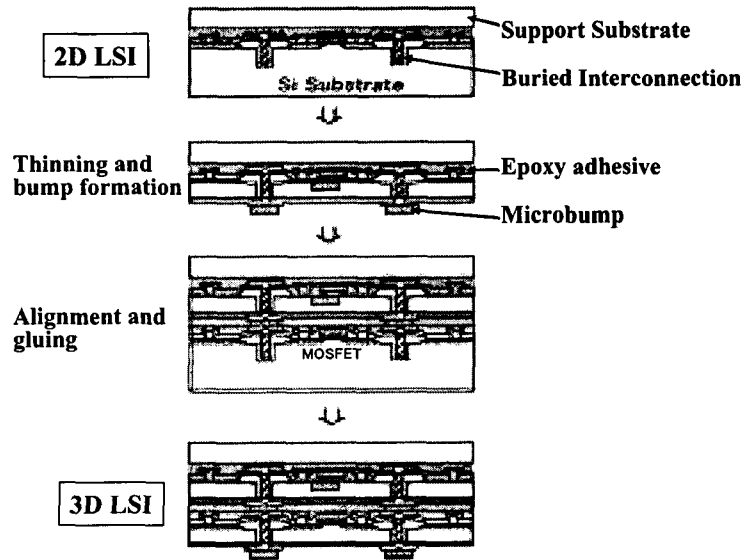
Semi-Fabless™

Super Smart Stack (SSS) Technology™

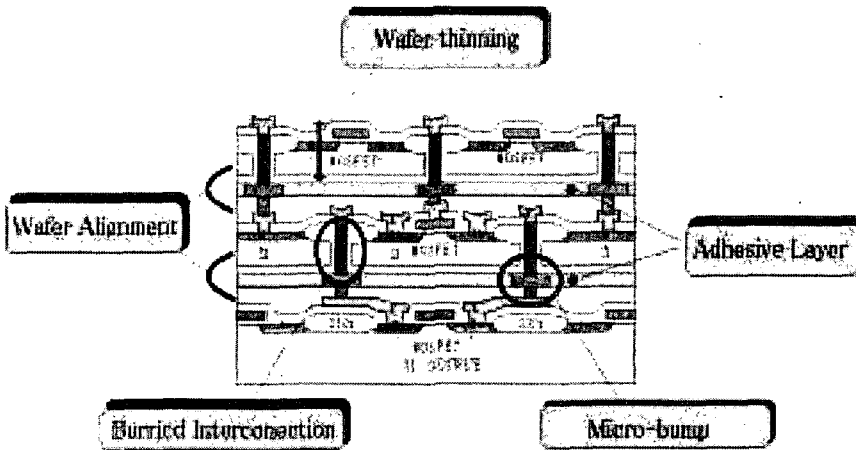
Super Chip with 3D Stacked Structure



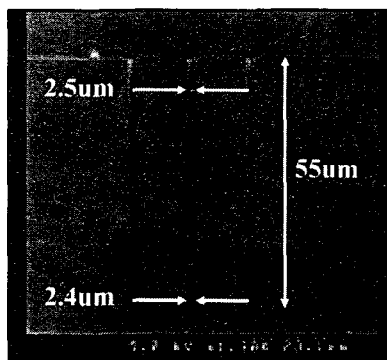
Fabrication Sequence of 3D LSI



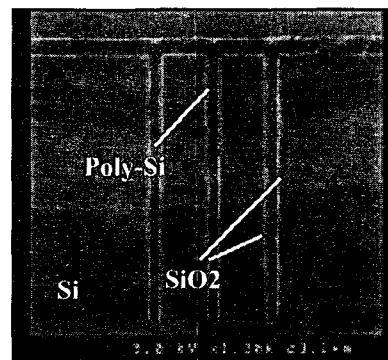
Key Technology for 3D LSI



SEM Cross Section of Buried Interconnection

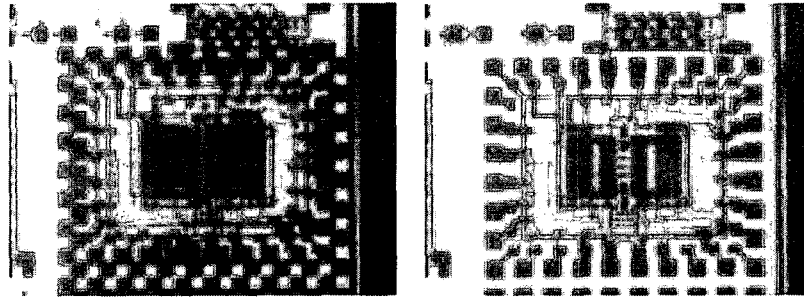


(a) Si deep trench etching



(b) Filling with Poly-Si

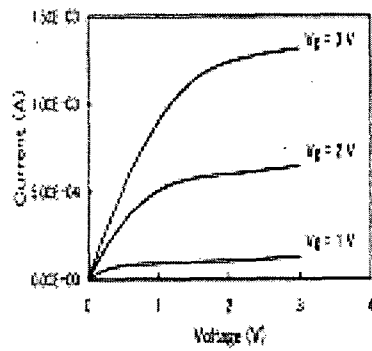
Infrared Images of 3D Test Chip Before and After Alignment



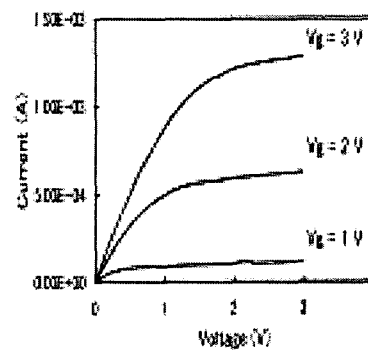
Before alignment

After alignment

I_d - V_d Characteristics of NMOSFET ($L_g=1.5\mu\text{m}$) Before and After Stacking



Before stacking(2D LSI chip)

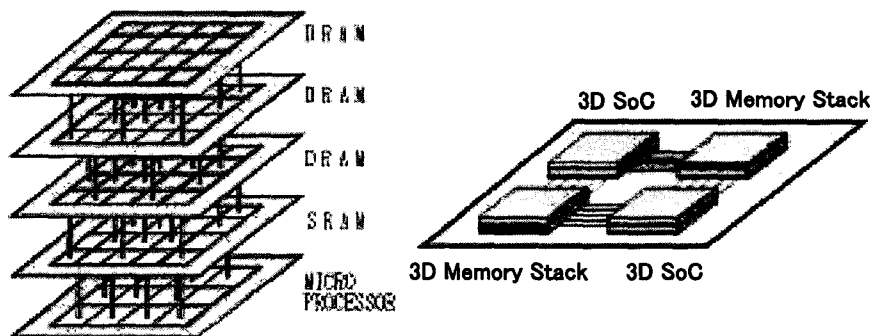


After stacking(3D LSI chip)

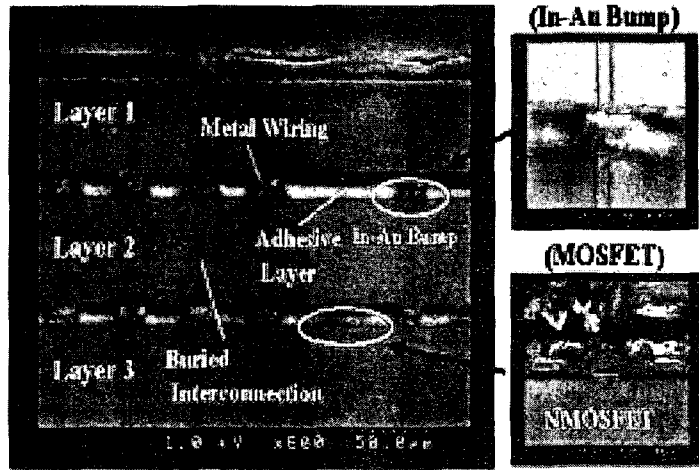
Publications of Fabricated 3D IC Chips

- 3-layer stacked image sensor chip (Mitsubishi)
Laser recrystallization (IEDM, 1986)
- 3-layer stacked image sensor chip (Tohoku Univ.) (IEDM, 1999)
Wafer bonding (Wafer non-transfer, Buried interconnection)
- 3-layer stacked memory chip (Tohoku Univ.) (IEDM, 2000)
Wafer bonding (Wafer non-transfer, Buried interconnection)
- 2-layer stacked image sensor chip (MIT) (ISSCC, 2001)
SOI wafer bonding
- 3-layer stacked artificial retina chip (Tohoku Univ.) (ISSCC, 2001)
Wafer bonding (Wafer non-transfer, Buried interconnection)
- 3-layer stacked microprocessor chip (Tohoku Univ.) (Cool Chips, 2002)
Wafer bonding (Wafer non-transfer, Buried interconnection)
- 2-layer stacked image sensor chip (MIT) (ISSCC, 2005)
SOI wafer bonding

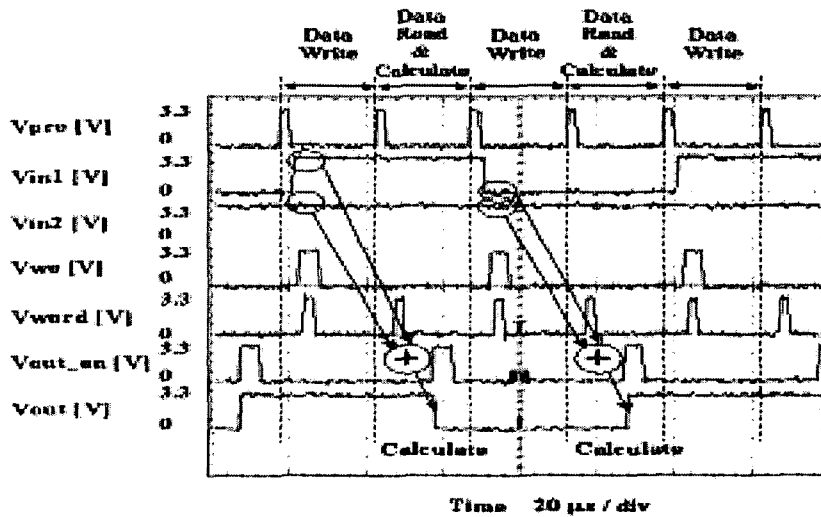
3D Computer Chip and 3D Multi-chip Module



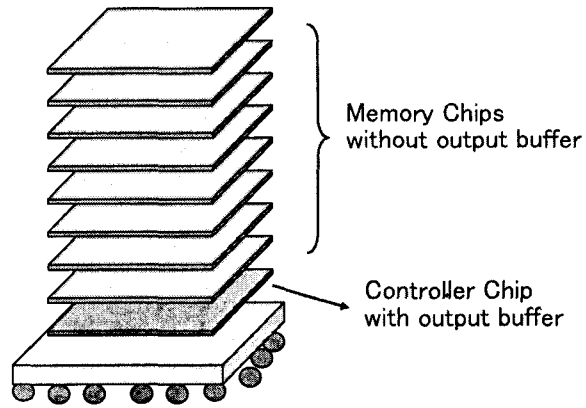
SEM Cross-Section of 3D Computer Test Chip



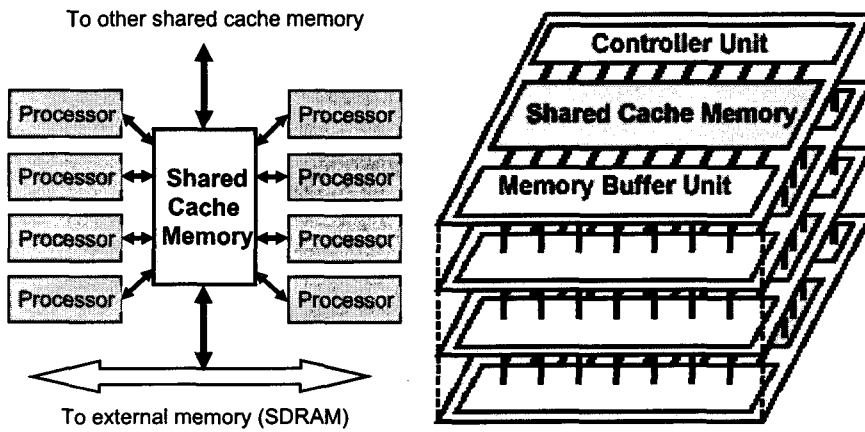
Measured Waveforms of 3D Computer Test Chip (SRAM layer: 3.3V, Processor layer: 2.5V)



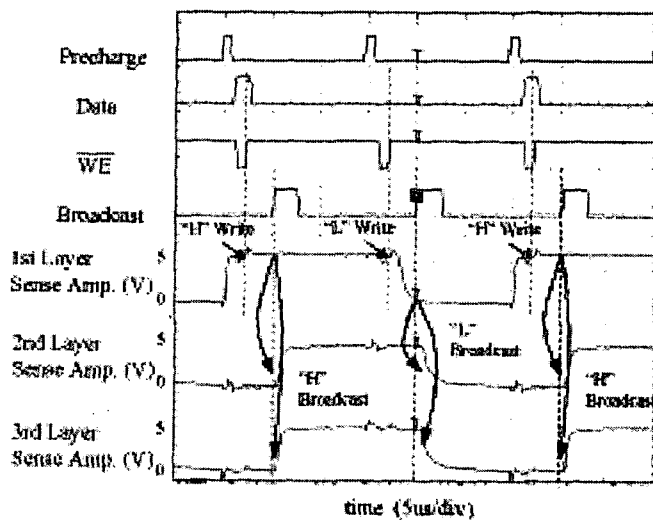
High Density, High Speed 3D Memory Chip



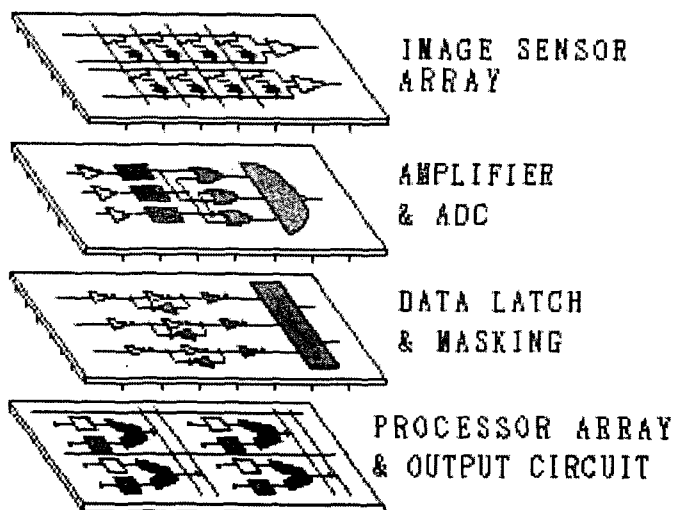
Shared Cache Memory with 3D Structure



Measured Waveforms in Broadcast Operation of 3D Shared Cache Memory

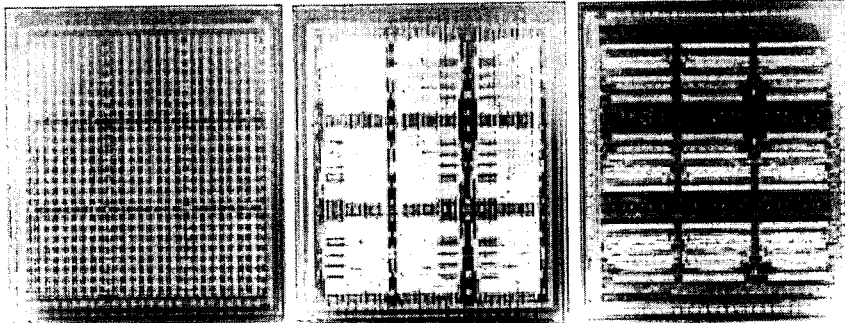


Real-Time Image Processing System with 3D Stacked Structure



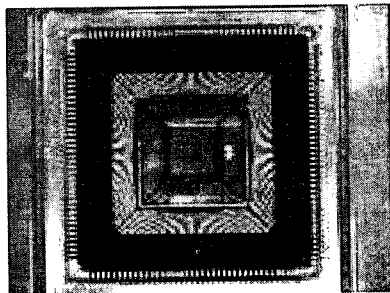
Photograph of respective chip in 3D stacked image sensor chip with three stacked layers

1st Layer (Photosensor circuit) 2nd Layer (Register circuit) 3rd Layer (ADC & ALU circuit)

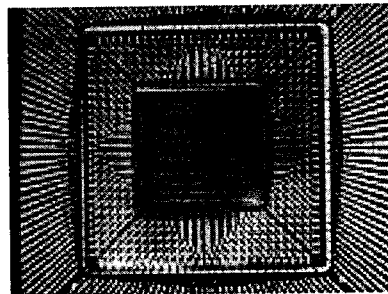


(Chip size : 6 mm x 6 mm, 112 pins)

Photograph of 3D Stacked Image Sensor Chip with Three Stacked Layers

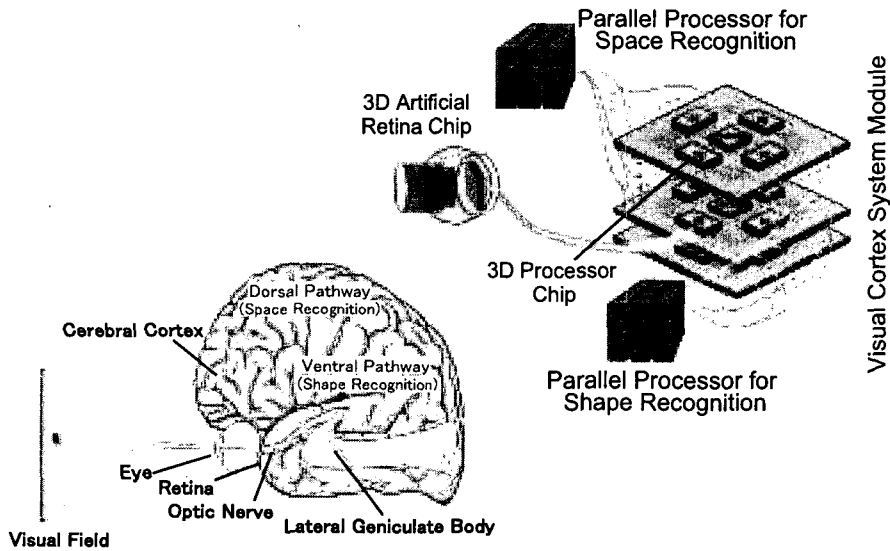


(a)

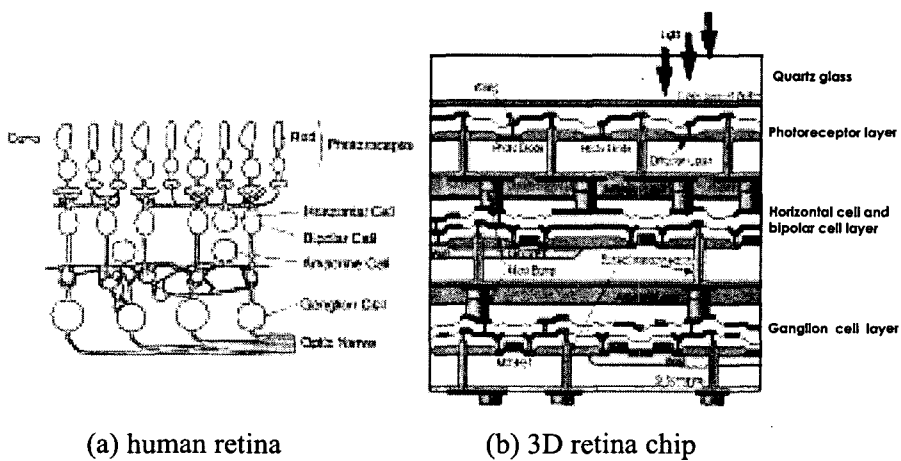


(b)

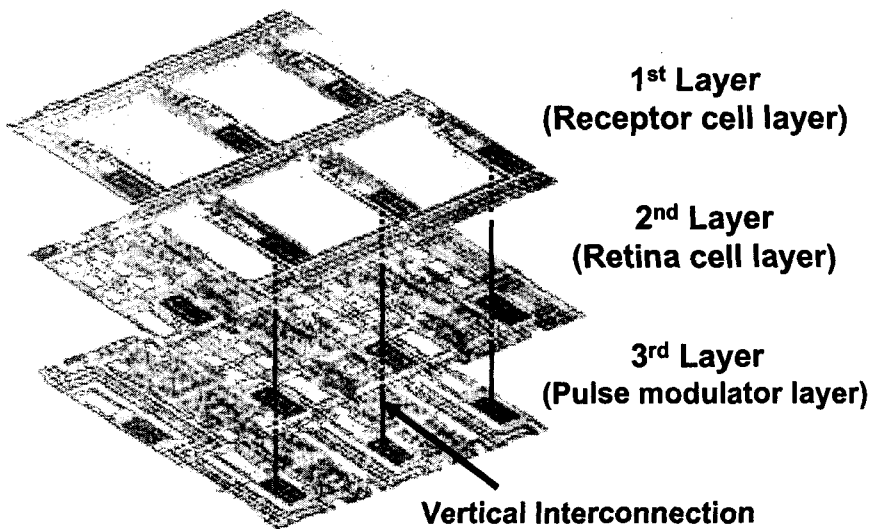
Brain-Type Information Processing System



Cross-Sectional Structures of Human Retina and 3D Artificial Retina Chip



Photograph of 3D Artificial Retina Chip

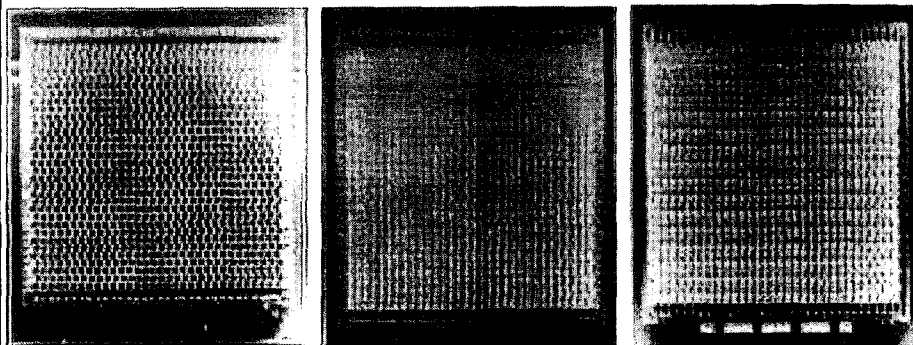


Photograph of Respective Chip in 3D Artificial Retina Chip with Three Stacked Layers

1st Layer
(Photoreceptor cell array)

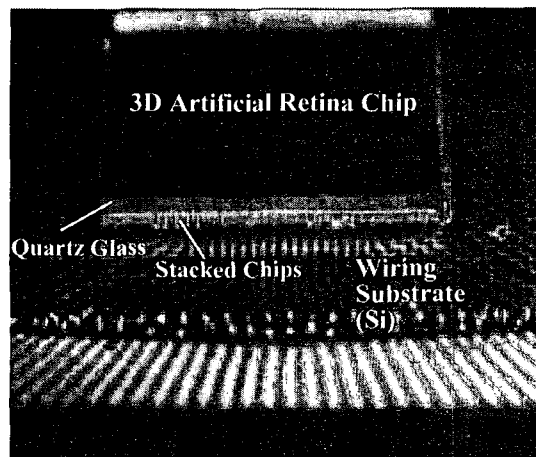
2nd Layer
(Bipolar, Horizontal, Ganglion cells array)

3rd Layer
(Pulse modulator cell array)



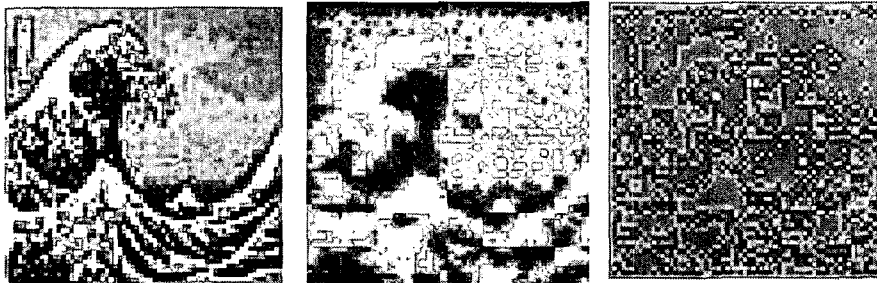
(Chip size : 6 mm x 6 mm, 112 pins)

Photomicrograph of 3D Artificial Retina Chip



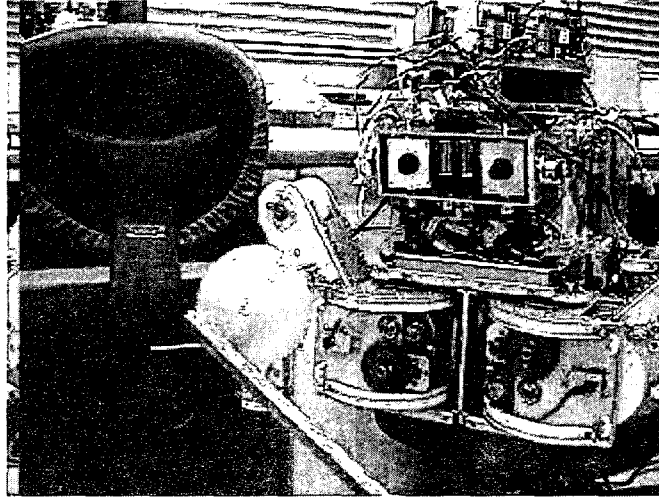
Visual Information Processing Using 3D Artificial Retina Chip

(64 × 64 photo receptor cells)



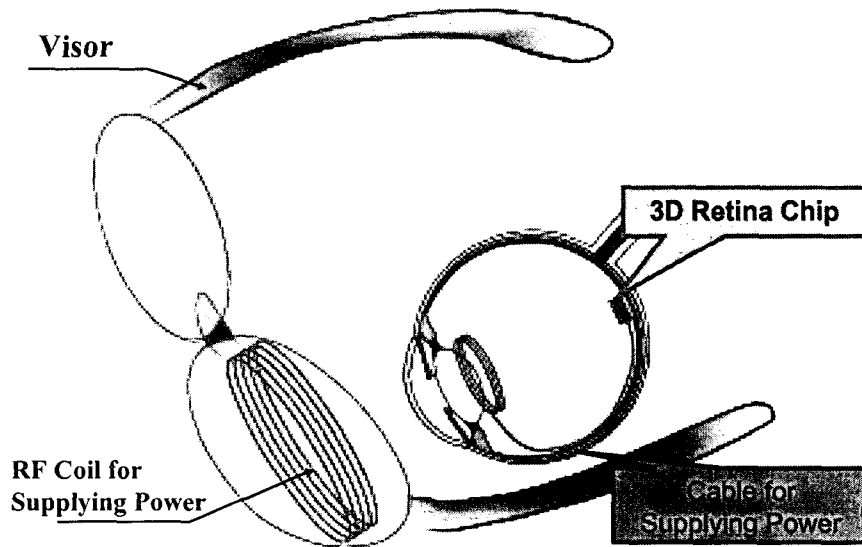
(a) Input pattern (b) Output pattern from photo circuit (c) Output pattern from Ganglion cell circuit

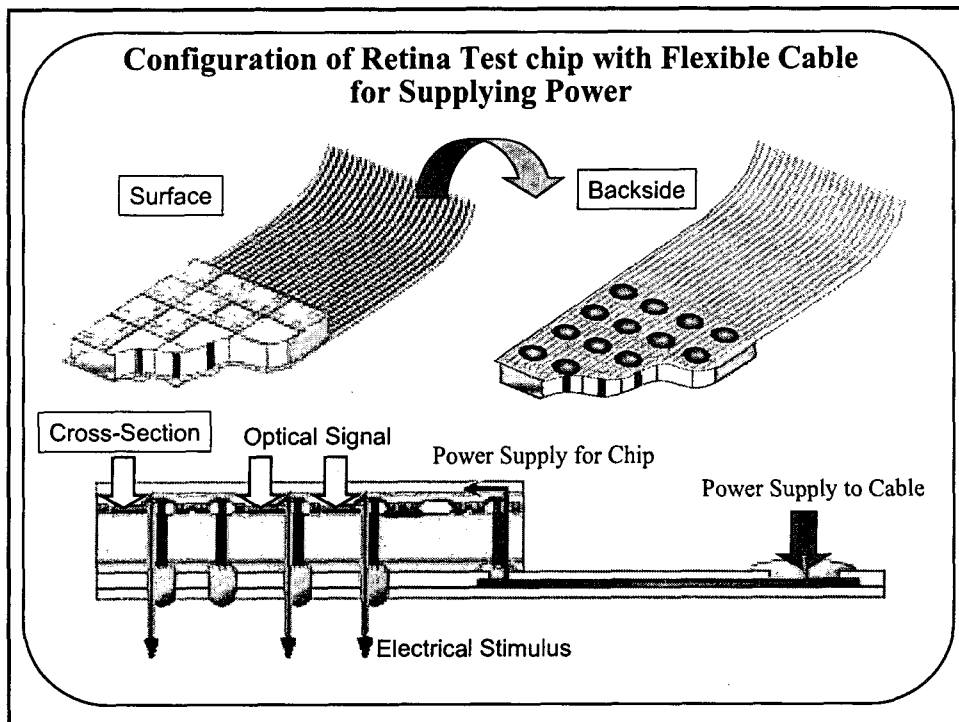
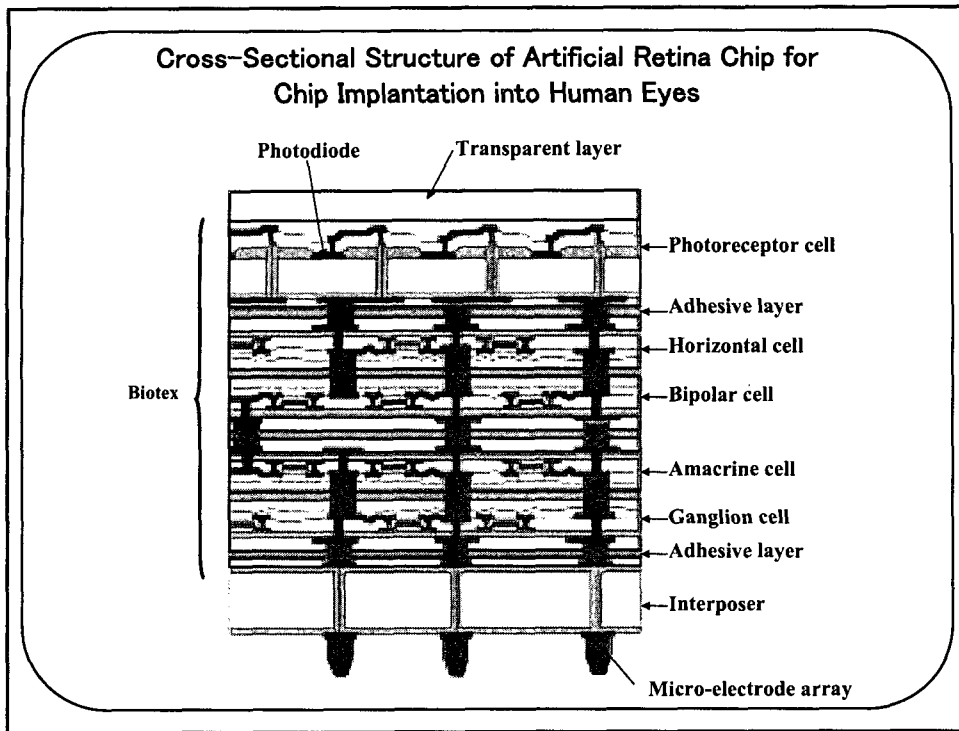
Robot Eyes with Smooth Pursuit Function Using Vision Chip



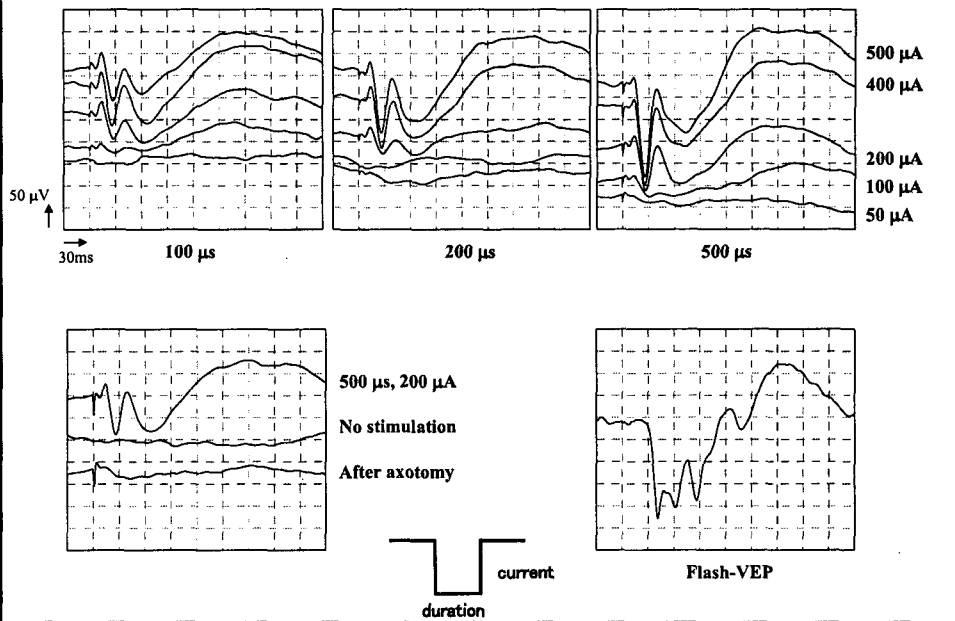
By courtesy of Prof. Konno (Dept. of Aerospace Engineering, Tohoku University)

3D Retina Chip Implantation into Human Eye

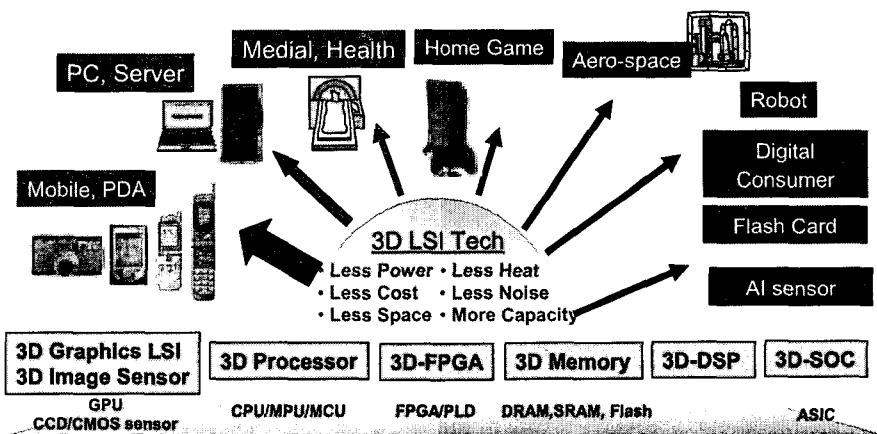




EPP (Electrically Evoked Potential) Signals Observed in Brain After Electrical Current Pulse Stimulation of Retina Cells



Application of 3D LSI Technology



Summary

- A new 3D integration technology using wafer-to-wafer and chip-to-wafer stacking method was described.**
- It was demonstrated that 3D microprocessor, 3D shared memory, 3D image processing chip and 3D artificial retina chip fabricated using 3D integration technology were successfully operated.**
- The possibility of applying 3D image processing chip and 3D artificial retina chip to Robot's eye was investigated.**
- The possibility of implanting 3D artificial retina chip into human eye was investigated.**